

XFEL + Single-turn Coilの論文が出版されました

昨年5月に行った、X線自由電子レーザー施設（SACLA）での可搬型一巻きコイル装置（PINK-01）を使った強磁場X線回折の実験結果がApplied Physics Lettersに論文として出版されました。

Applied Physics Letters

ARTICLE

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Generating 77 T using a portable pulse magnet for single-shot quantum beam experiments

Cite as: Appl. Phys. Lett. **120**, 142403 (2022); doi: [10.1063/5.0088134](https://doi.org/10.1063/5.0088134)

Submitted: 13 February 2022 · Accepted: 18 March 2022 ·

Published Online: 5 April 2022 · Publisher error corrected: 11 April 2022



View Online



Export Citation



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ABSTRACT

We devised a portable system that generates pulsed high magnetic fields up to 77 T with 3 μ s duration. The system employs the single turn coil method, a destructive way of field generation. The system consists of a capacitor of 10.4 μ F, a 30 kV charger, a mono air-gap switch, a triggering system, and a magnet clamp, which weighs less than 1.0 tons in total and is transportable. The system offers opportunities for single-shot experiments at ultrahigh magnetic fields in combinations with novel quantum beams. The single-shot x-ray diffraction experiment using a x-ray free-electron laser at 65 T is presented. We comment on the possible update of the system for the generation of 100 T.

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